



Eye Tracking Research & Applications Symposium

March 22th – 24th, 2010
Omni Austin Hotel Downtown
Austin, TX
www.e-t-r-a.org

Sponsored By



ETRA 2010 will be the sixth biennial symposium in a series that focuses on all aspects of eye movement research across a wide range of disciplines. The goal of ETRA is to bring together computer scientists, engineers and behavioral scientists in support of a common vision of enhancing eye tracking research and applications. ETRA 2010 is being organized in conjunction with the European Communication by Gaze Interaction (COGAIN) research network that specializes in gaze-based interaction for the benefit of people with physical disabilities.

Symposium Themes

Advances in Eye Tracking Technology and Data Analysis

Eye tracking systems, calibration algorithms, data analysis techniques, noise reduction, predictive models, 3D POR measurement, low cost and natural light systems.

Visual Attention and Eye Movement Control

Studies of eye movements in response to natural stimuli, driving studies, web use and usability studies.

Eye Tracking Applications

Gaze-contingent displays, attentive user interfaces, gaze-based interaction techniques, security systems, multimodal interfaces, augmented and mixed reality systems, ubiquitous computing.

Special Theme: Eye Tracking and Accessibility

Eye tracking has proved to be an effective means of making computers more accessible when the use of keyboards and mice is hindered by the task itself (such as driving), or by physical disabilities. We invite submissions that explore new methodological strategies, applications, and results that use eye tracking in assistive technologies for access to desktop applications, for environment and mobility control, and for gaze control of games and entertainment.

Submissions

Two categories of submissions are being sought – Full Papers and Short Papers.

Full papers must be submitted electronically through the ETRA 2010 website and conform to the ACM SIGGRAPH proceedings category 2 format. Full papers submissions can have a maximum length of eight pages. Full papers submissions should be made in double-blind format, hiding authors' names and affiliations and all references to the authors' previous work. Those wishing to submit a full paper must submit an abstract in advance to facilitate the reviewing process. Accepted papers will be published in the ETRA 2010 proceedings, and the authors will give a 20 minute oral presentation of the paper at the conference.

Short papers may present work that has smaller scope than a full paper or may present late breaking results. These must be submitted electronically through the ETRA 2010 submission website and conform to the ACM SIGGRAPH proceedings category 3 format. Short paper submissions have a maximum length of four pages (but can be as short as a one-page abstract). Given the time constraints of this type of paper, submissions must be made in camera-ready format including authors' names and affiliations. Accepted submissions will be published in the ETRA 2010 proceedings. Authors will present a poster at the conference, and authors of the most highly rated submissions will give a 10 minute presentation of the paper in a Short Papers session.

All submissions will be peer-reviewed by members of an international review panel and members of the program committee. Best Paper Awards will be given to the most highly ranked Full Papers and Short Papers.

Full Papers Deadlines

Sep. 30 th , 2009	Full Papers abstract submission deadline
Oct. 7 th , 2009	Full Papers submission deadline
Nov. 13 th , 2009	Acceptance notification

Short Papers Deadlines

Dec. 2 th , 2009	Short Papers submission deadline
Jan. 8 th , 2010	Short Papers acceptance notification
Jan. 15 th , 2010	All camera ready papers due

Conference Co-Chairs

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